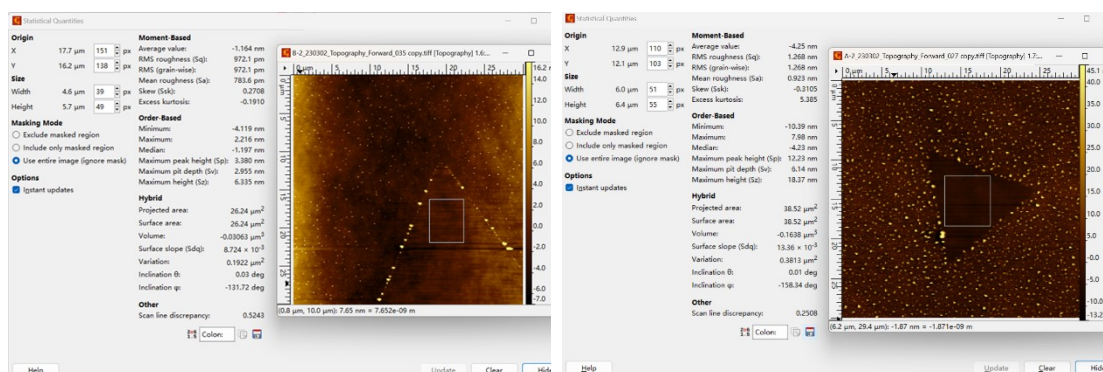
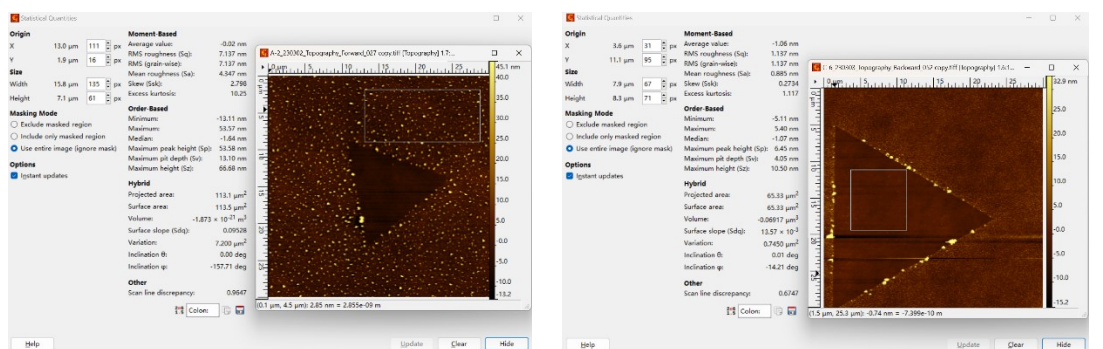


## Supplementary Information



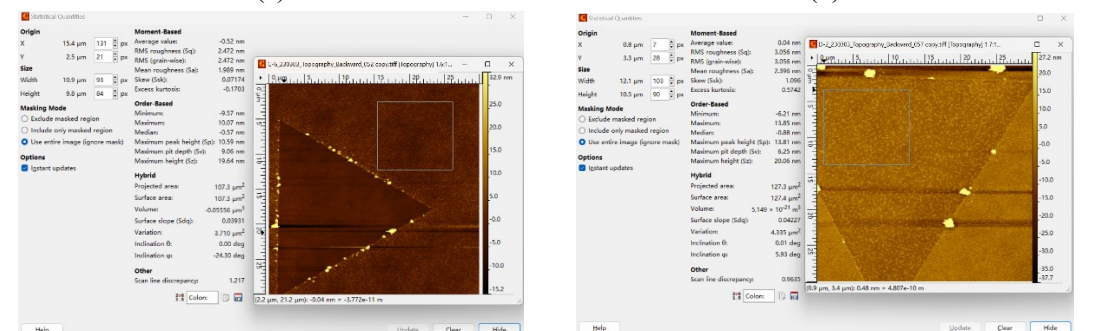
(a)

(b)



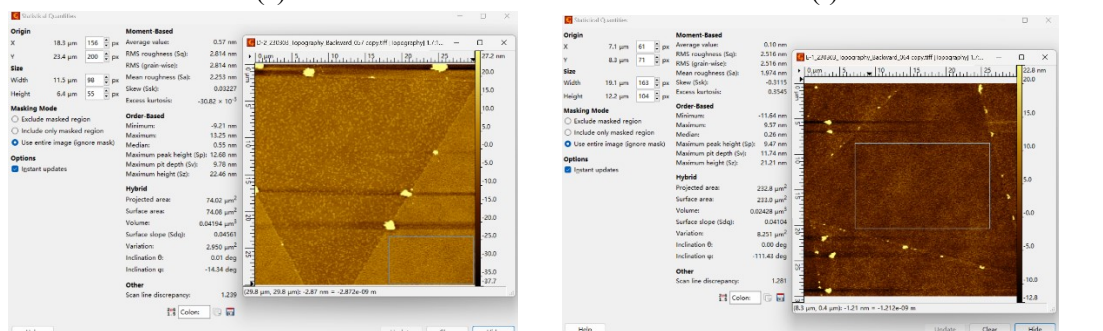
(c)

(d)



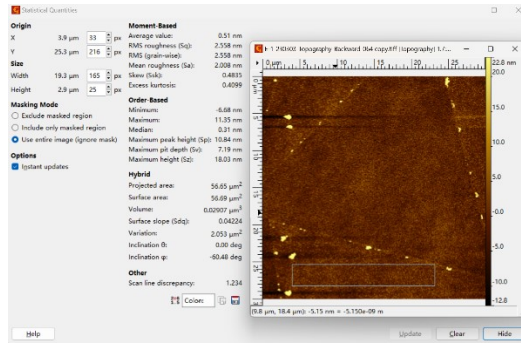
(e)

(f)



(g)

(h)



(i)

Fig. S1 Roughness of  $\text{WS}_2$  on  $\text{Si}/\text{SiO}_2$  (a), 10nm  $\text{CsSnBr}_3$  on  $\text{WS}_2$  (b) on  $\text{Si}/\text{SiO}_2$  (c), 30nm  $\text{CsSnBr}_3$  on  $\text{WS}_2$  (d) on  $\text{Si}/\text{SiO}_2$  (e), 50nm  $\text{CsSnBr}_3$  on  $\text{WS}_2$  (f) on  $\text{Si}/\text{SiO}_2$  (g), 70nm  $\text{CsSnBr}_3$  on  $\text{WS}_2$  (h) and on  $\text{Si}/\text{SiO}_2$  (i)

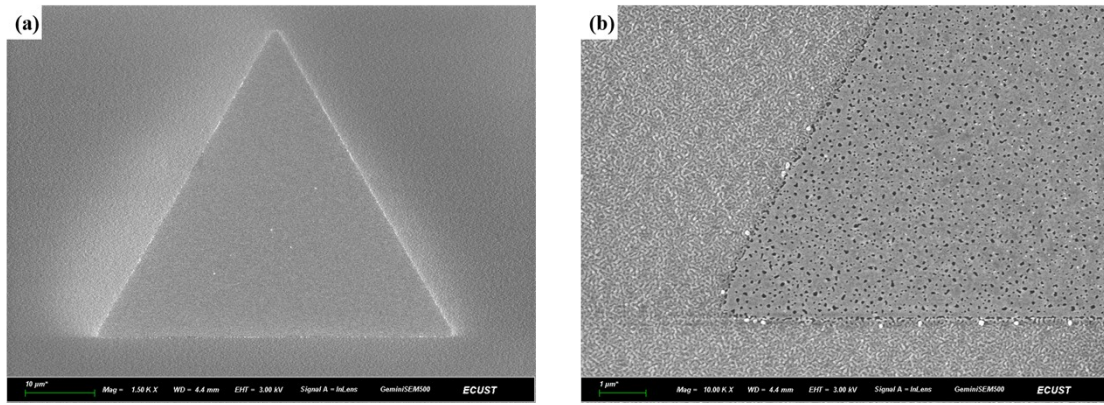


Fig.S2 FESEM images of 10nm CsSnBr<sub>3</sub> on WS<sub>2</sub> on Si/SiO<sub>2</sub> (a) × 1500 and (b) × 10000.

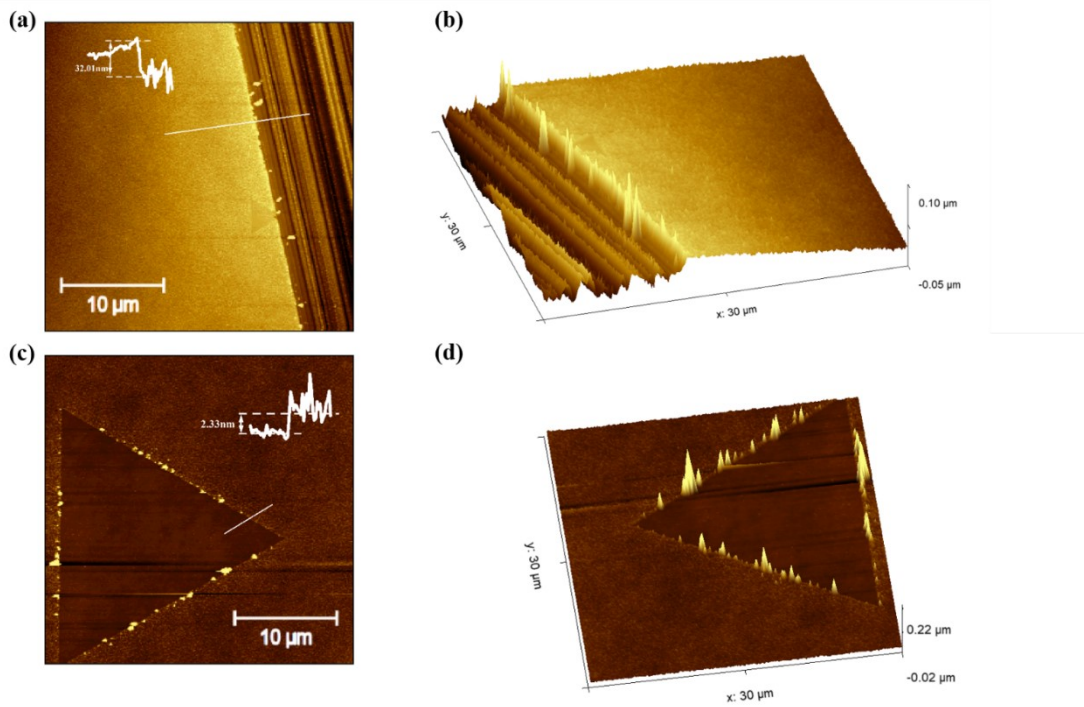


Fig.S3 AFM images of 30nm CsSnBr<sub>3</sub> on Si/SiO<sub>2</sub> (a) top view, (b) 3D image, height profile measured along the white line; AFM images of 30nm CsSnBr<sub>3</sub> on monolayer WS<sub>2</sub> (c) top view, (d) 3D image.

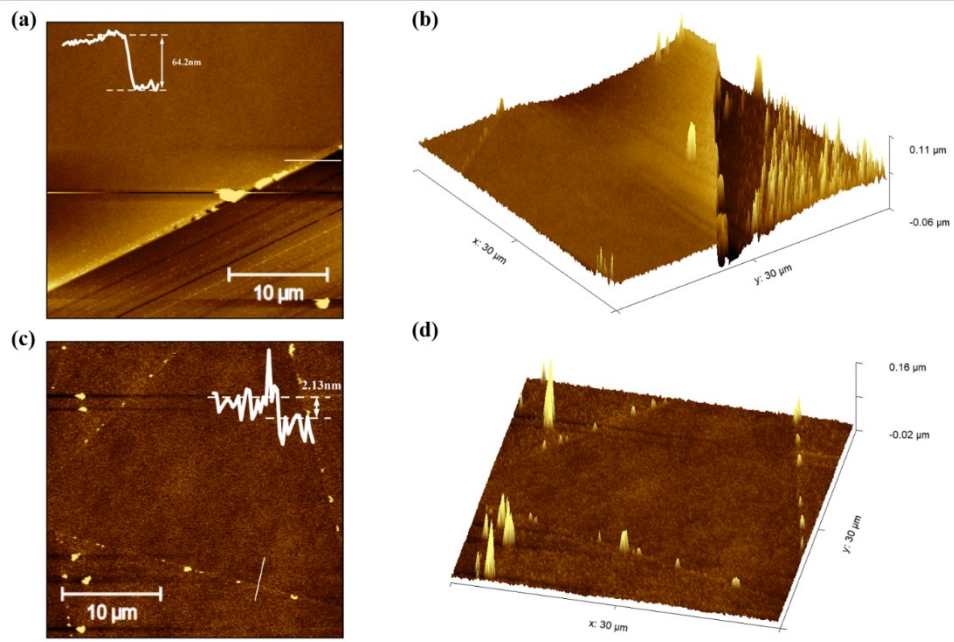


Fig.S4 AFM images of 70nm CsSnBr<sub>3</sub> on Si/SiO<sub>2</sub> (a) top view, (b) 3D image, height profile measured along the white line; AFM images of 70nm CsSnBr<sub>3</sub> on monolayer WS<sub>2</sub> (c) top view, (d) 3D image

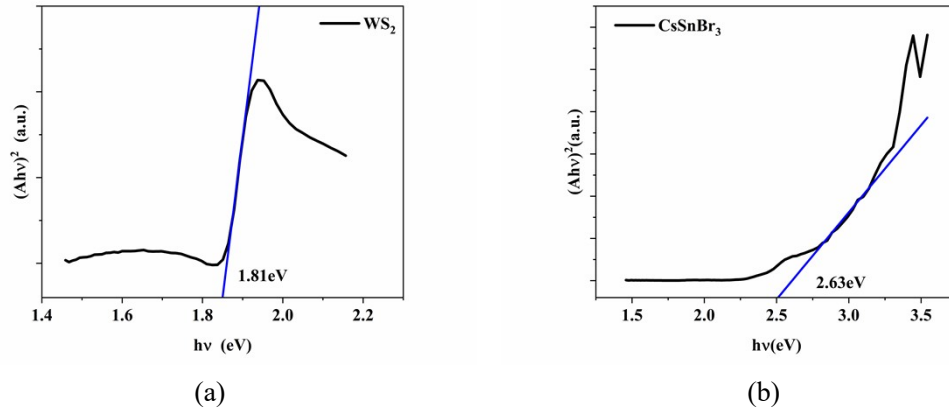


Fig.S5 Tauc's plot of monolayer  $\text{WS}_2$  and 70nm  $\text{CsSnBr}_3$  on quartz.

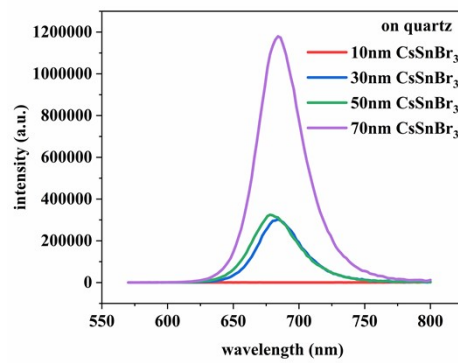
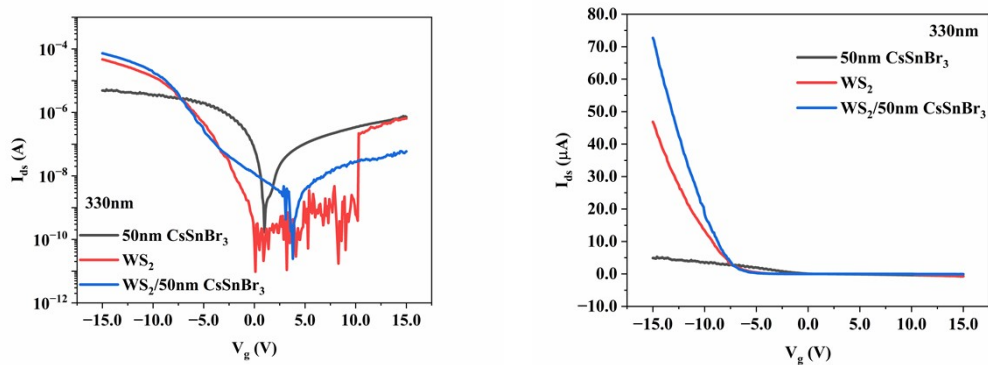
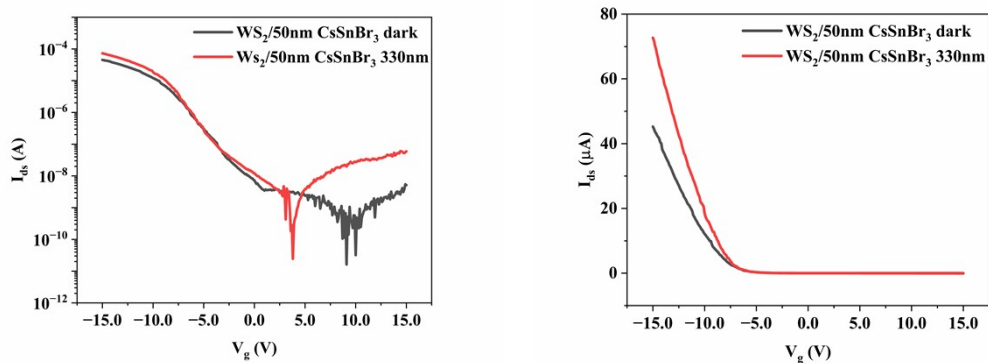


Fig.S6 PL of  $\text{CsSnBr}_3$  with various thickness on  $\text{Si}/\text{SiO}_2$



(a)



(b)

Fig.S7 Transfer curves of isolated  $WS_2$  and  $CsSnBr_3$ , and the heterostructure of  $WS_2/50nm$   $CsSnBr_3$  at 330nm photo-excitation condition in logarithm and linear scale (a); Transfer curves of the heterostructure  $WS_2/50nm$   $CsSnBr_3$  at dark and 330nm photo-excitation conditions in logarithm and linear scale (b).

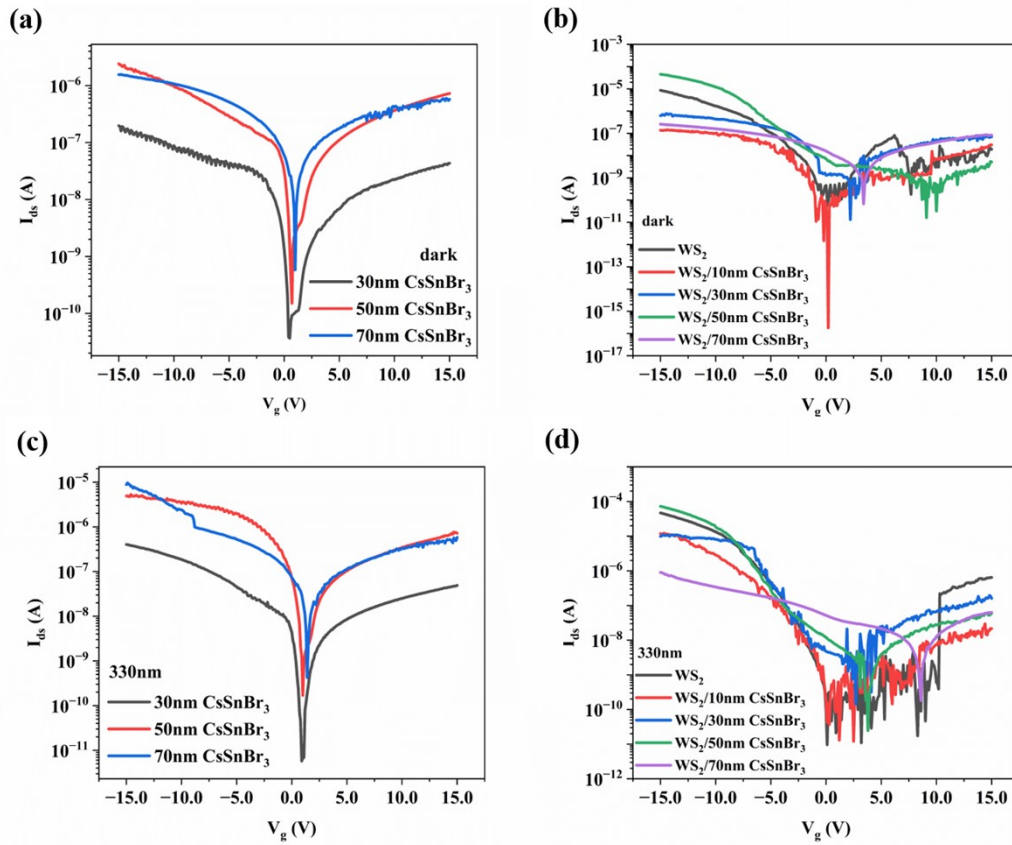


Fig.S8 Transfer curves of isolated CsSnBr<sub>3</sub> and the heterostructures of WS<sub>2</sub>/CsSnBr<sub>3</sub> with various CsSnBr<sub>3</sub> thicknesses at dark (a) (b) and 330nm photo-excited (c) (d) conditions in logarithm scale

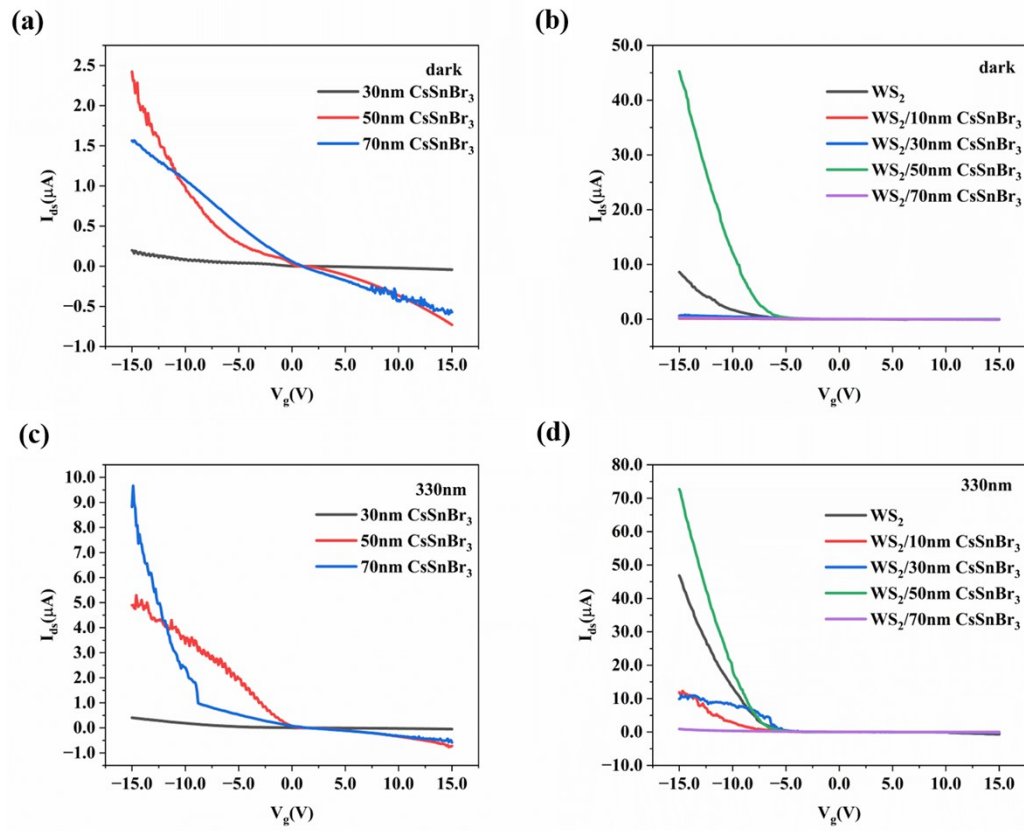


Fig.S9 Transfer curves of isolated CsSnBr<sub>3</sub> and the heterostructures of WS<sub>2</sub>/CsSnBr<sub>3</sub> with various CsSnBr<sub>3</sub> thicknesses at dark (a) (b) and 330nm photo-excited (c) (d) conditions in linear scale



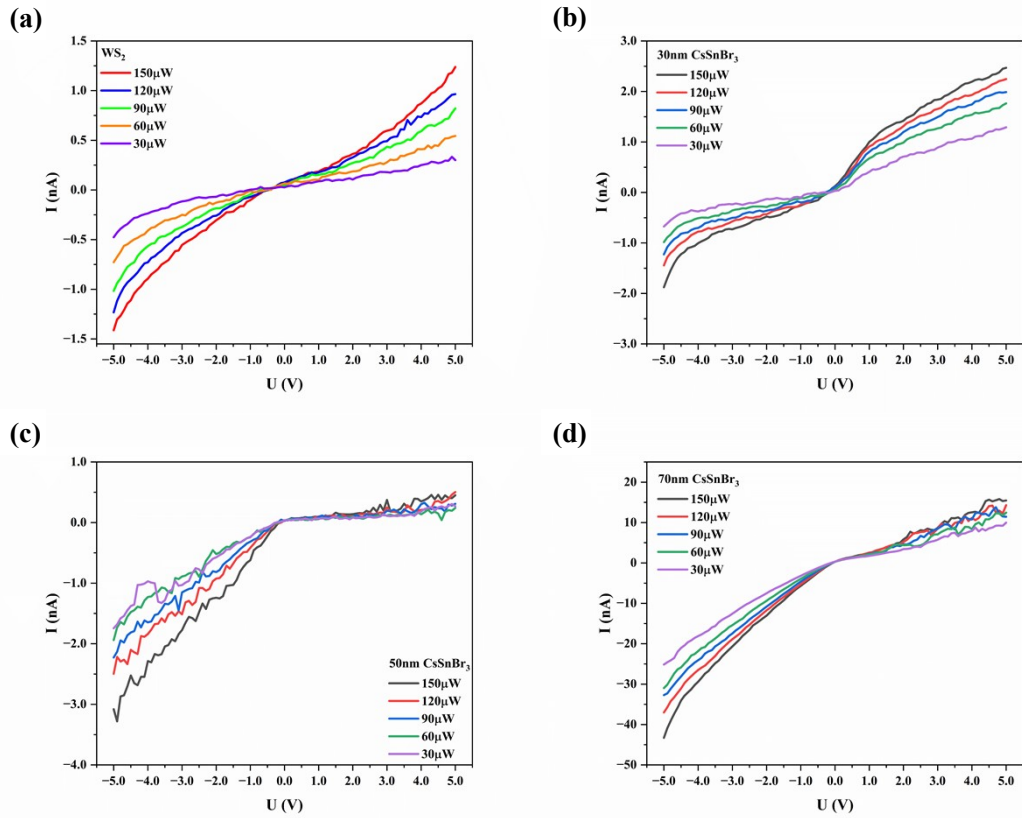


Fig.S10  $I_{\text{ph}}$ -optical power at the wavelength of 330nm for (a) monolayer  $\text{WS}_2$ , (b)30nm, (c)50nm and (d) 70nm  $\text{CsSnBr}_3$  on  $\text{Si}/\text{SiO}_2$

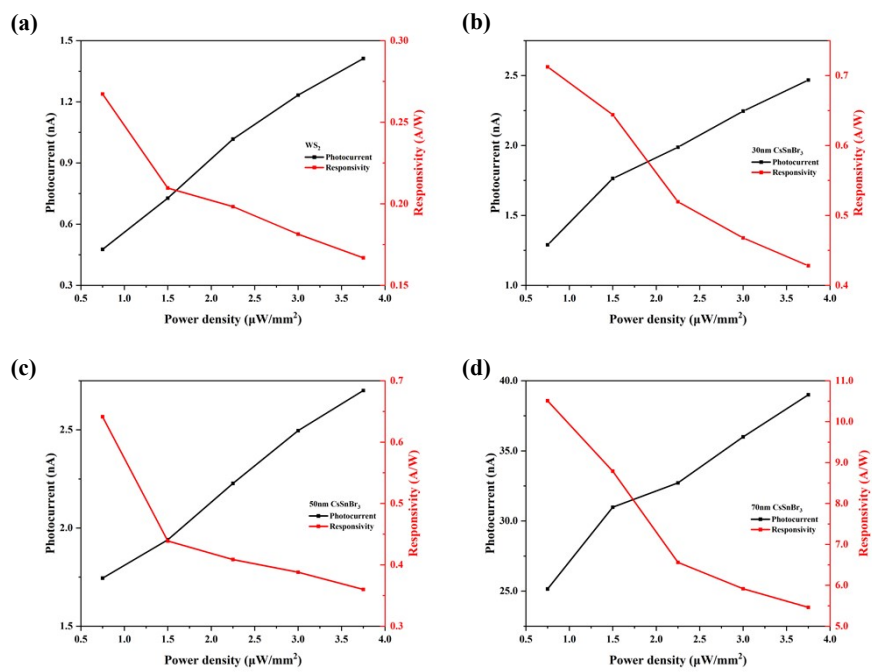


Fig.S11 Dependence of responsivity ( $R$ ) and  $I_{\text{ph}}$  on optical power at the wavelength of 330nm for (a) monolayer  $\text{WS}_2$ , (b)30nm, (c)50nm and (d) 70nm  $\text{CsSnBr}_3$  on  $\text{Si}/\text{SiO}_2$

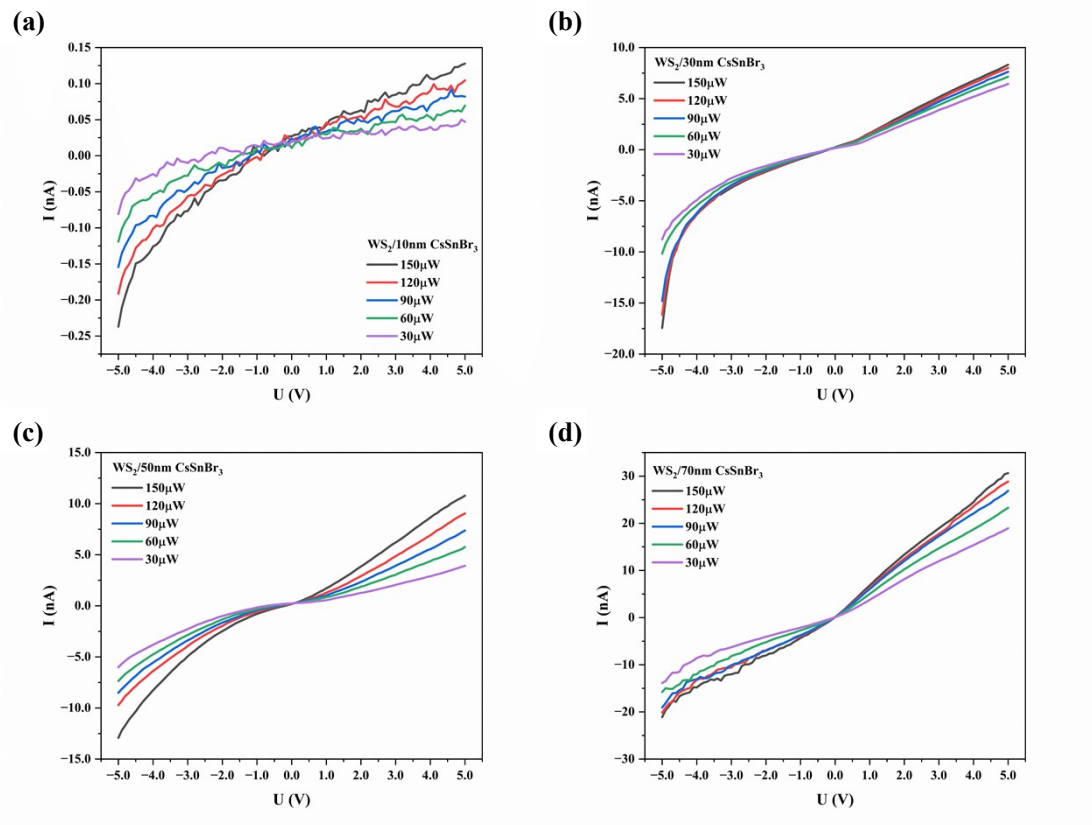


Fig.S12  $I_{ph}$ -optical power at the wavelength of 330nm for the heterostructures of  $WS_2/CsSnBr_3$  with  $CsSnBr_3$  thickness of (a) 10nm, (b)30nm, (c)50nm, (d) 70nm

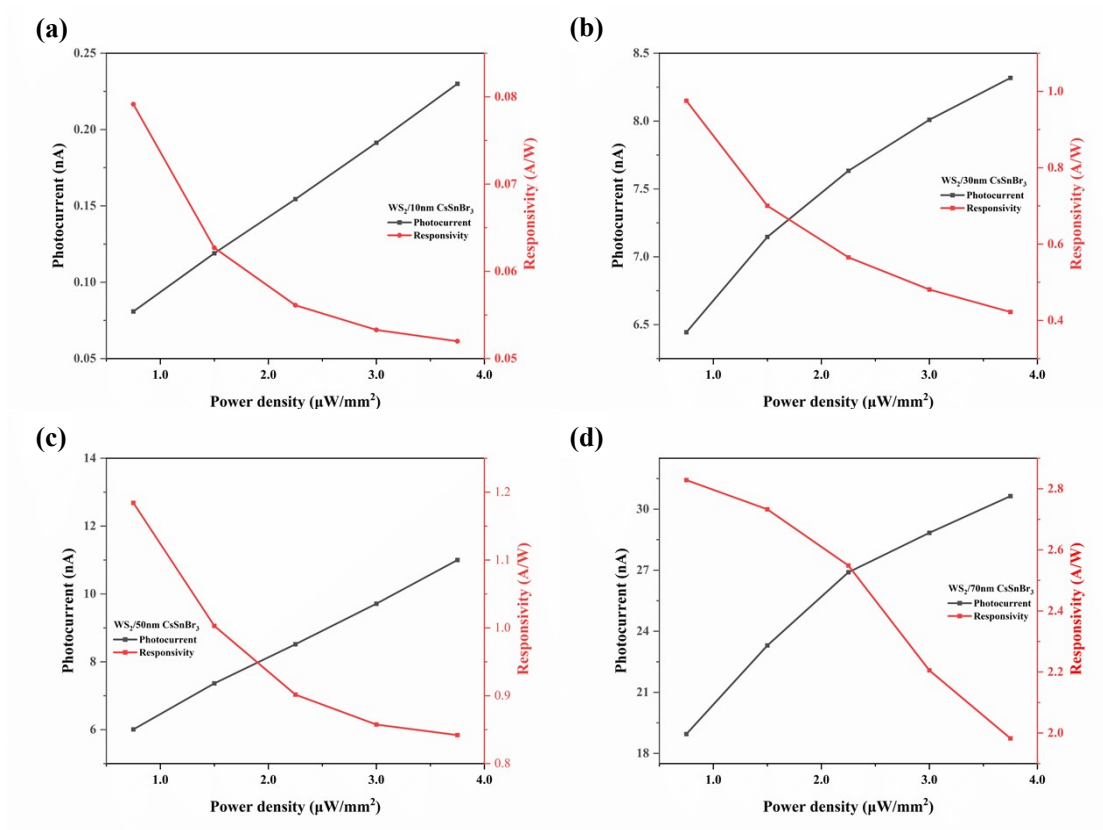


Fig.S13 Dependence of responsivity (R) and  $I_{ph}$  on optical power at the wavelength of 330nm for the heterostructures of  $WS_2/CsSnBr_3$  with  $CsSnBr_3$  thickness of (a) 10nm, (b)30nm, (c)50nm, (d) 70nm

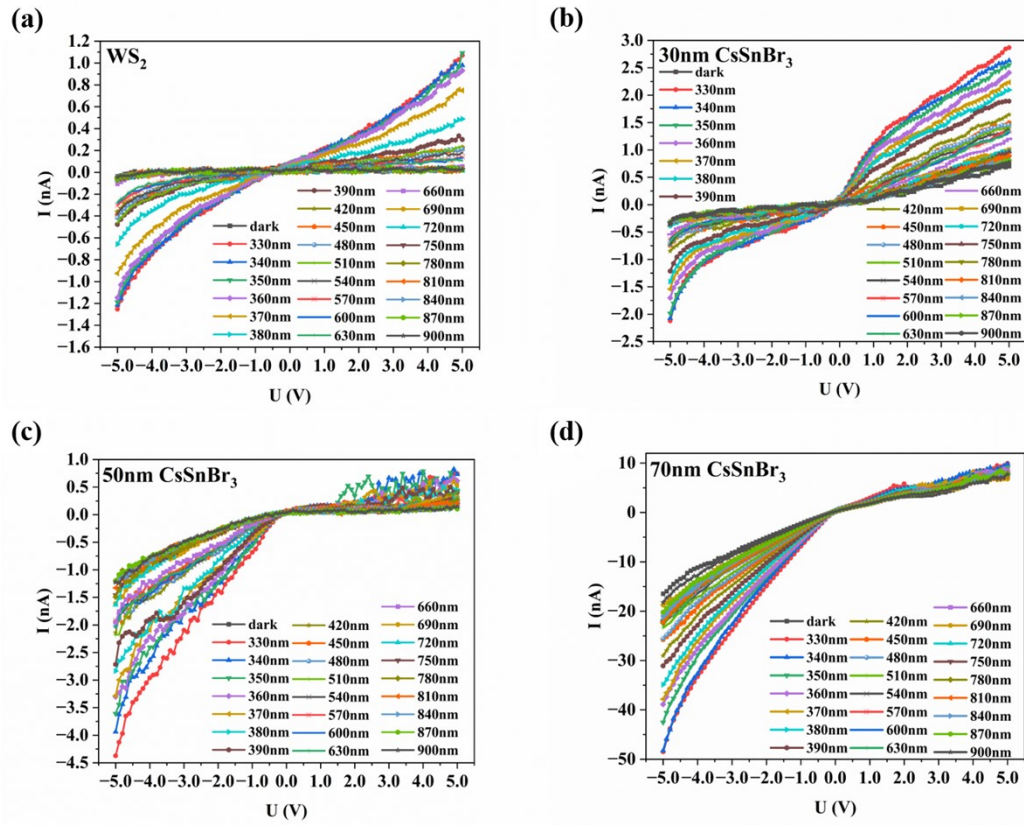


Fig.S14  $I_{ph}$ -wavelength under the optical power of  $0.6\mu w/mm^2$  for (a) monolayer  $WS_2$ ,  
 (b)30nm, (c)50nm and (d) 70nm  $CsSnBr_3$  on  $Si/SiO_2$

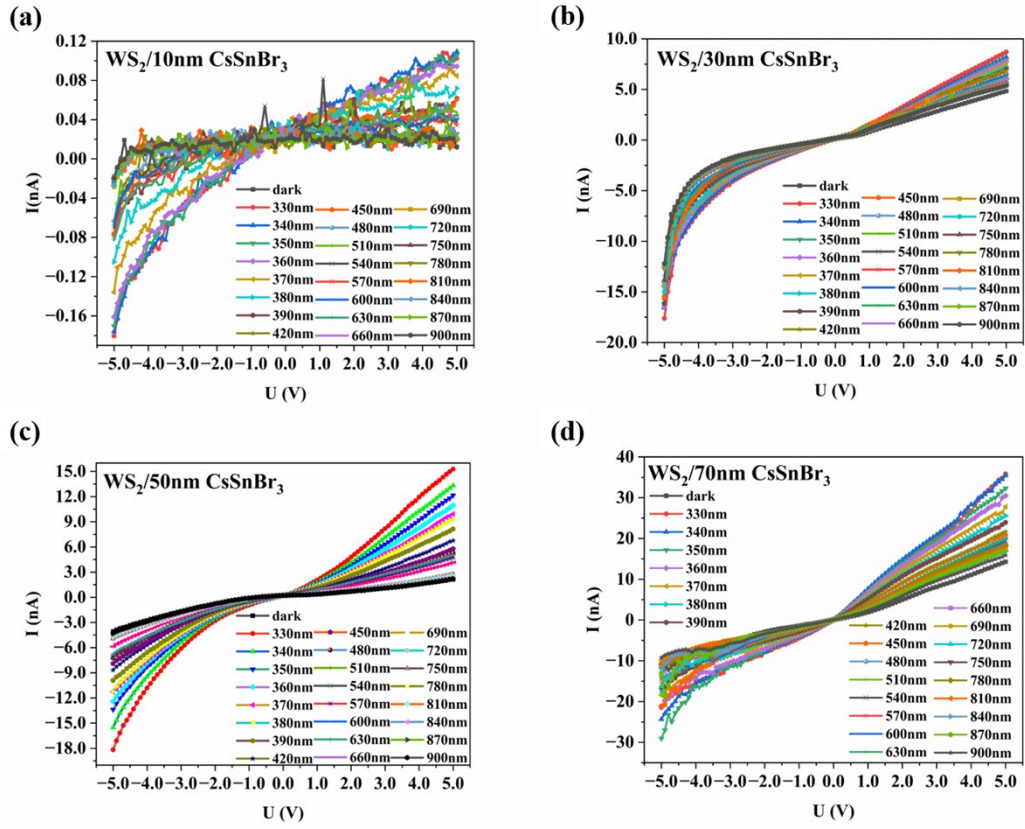


Fig.S15  $I_{ph}$ -wavelength under the optical power of  $0.6\mu\text{W}/\text{mm}^2$  for the heterostructures of  $\text{WS}_2/\text{CsSnBr}_3$  with  $\text{CsSnBr}_3$  thickness of (a)10nm, (b)30nm, (c)50nm and (d)70nm

Table.S1 Comparison of our work with previously reported Sn-based perovskite photodetector

Sensing materials	Response wavelength (nm)	Responsivity (A/W)	$D^* (\times 10^{10} \text{ cmW}^{-1} \text{ Hz}^{1/2})$	Response time (ms)	ref
$\text{MASnI}_3$ NWs		0.47	$8.80 \times 10^5$	1500/400	1
$\text{MAPb}_{0.5}\text{Sn}_{0.5}\text{I}_3$	905	0.514	$1.50 \times 10^{11}$		2
$\text{CsSnI}_3$ NWs	940	0.054	$3.85 \times 10^{10}$	83.8/243.4	3
$\text{CsSnI}_3$	850	0.257	$1.5 \times 10^{11}$	0.35/1.6	4
$\text{CsSnI}_3/\text{BMIMCl}$	405	0.237	$1.18 \times 10^{12}$	0.23/0.19	5
50nm $\text{CsSnBr}_3$	330	0.36	$8.62 \times 10^{10}$	340/470	This work
$\text{WS}_2/50\text{nm CsSnBr}_3$	330	1.62	$2.11 \times 10^{11}$	150/620	This work

### CVD growth of WS<sub>2</sub>

The WS<sub>2</sub> nanosheets are fabricated by the chemical vapor deposition (CVD) processing on Si/SiO<sub>2</sub> substrate in a multitemperature zone tubular furnace as depicted in Fig.1(a). The Si/SiO<sub>2</sub> substrates are beforehand ultrasonically cleaned by the acetone, isopropyl alcohol (IPA) and deionized (DI) water subsequently, and then dried by pure nitrogen (N<sub>2</sub>) to ensure the crystallization quality of WS<sub>2</sub> nanosheets. 0.4 g Sulphur powder is placed in the position of the center and near inlet gas entrance of the quartz tube which is filled with the inert nitrogen gas under a constant flow (80 sccm). N<sub>2</sub> gas was serviced as the carrier gas. In the high temperature zone, the 40 mg WO<sub>3</sub> and 8mg NaCl are mixed in a sapphire boat along with the Si/SiO<sub>2</sub> substrate placed upside down on it at the downstream. For growth of WS<sub>2</sub> nanosheets, two temperature zones are heated to the temperature of 150 and 830°C, respectively. The size of the as-prepared WS<sub>2</sub> nanosheets can be tuned by the reaction time, which is varied from 5 to 20 minutes. The pressure inside was maintained at  $4 \times 10^4$  Pa, and then the furnace was naturally cooled down to the room temperature.

### Thermal evaporation of CsSnBr<sub>3</sub>

The CsSnBr<sub>3</sub> perovskite films are fabricated by the co-evaporation of the CsBr and SnBr<sub>2</sub> source materials simultaneously in a multisource thermal evaporator (LiNing 386SA organic multisource thermal evaporation system, Shenyang, China). The base vacuum of the chamber was kept at  $2 \times 10^{-4}$  Pa. The CsSnBr<sub>3</sub> films are annealed at the temperature of 75°C during the thermal evaporation process, namely the in-situ annealing is performed to form the crystalline CsSnBr<sub>3</sub>. The thickness of the CsSnBr<sub>3</sub> films can be monitored by the separated quartz crystal oscillators.

### Device Fabrication

Photoresist was spin-coated on as-grown WS<sub>2</sub> as mask. Photoresist patterns for electrodes were conducted through UV photolithography and development. After that, metal electrodes, Ag were deposited by using thermal evaporator and finally lifted off using remover. Then the as-fabricated electrodes were cleaned by DI water and dried by pure nitrogen. The electrodes were subsequently annealed at 350°C in N<sub>2</sub> for 30 min to reduce the contact resistance. Finally, CsBr and SnBr<sub>2</sub> were deposited to obtain WS<sub>2</sub>/CsSnBr<sub>3</sub> devices. The diagram of the formed heterostructure photodetectors is shown in Fig(1) with the Ag electrodes on Si/SiO<sub>2</sub> substrates whose width and length of the channel are kept at 20 and 100µm.

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- 4 F. R. Cao, W. Tian, M. Wang, M. Wang and L. Li. *InfoMat*. 2020, **2**, 577-584.
- 5 Z. Gao, H. Zhou, K. L. Dong, C. Wang, J. Y. Wei, Z. Li, J. S. Li, Y. J. Liu, J. Zhao and G. J. Fang. *Nano-Micro Lett.* 2022, **14**, 215.